

G-RAD Workshop - Grenoble Radiation Testing of semiconductor devices and systems



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Recent advances in pulsed X-ray single-event testing

Thursday, 10 December 2020 10:40 (25 minutes)

Pulsed x-rays have been demonstrated as a powerful tool that is complementary and supplementary to energetic particle and pulsed laser SEE testing. This talk will address the application of pulsed x-rays for SEE testing of microelectronic devices. Advantages and limitations of x-ray SEE testing will be discussed. The current test setup at the Advanced Photon Source at Argonne National Laboratory will be described in detail and several examples from recent work will be presented.

Presenter: LALUMONDIERE, Stephen (The Aerospace Corporation)

Session Classification: Session 4 - Alternative Testing Methods